

A&D's Opportunity in EB / FIB Products NANO KOREA 2010 in Seoul, Korea

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NANO KOREA 2010 with IEEE NANO 2010, the 8th International Symposium & Exhibition, was held at KINTEX in Gyunggi Province, Korea from August 17-20, 2010.

The exhibition was held concurrently with MicroTech World with Laser Korea 2010, the 3rd International Microtech/MEMS Exhibition & Conference and Printed Electronics Korea, the 1st International Printed Electronics TechExpo. (Web site: <http://nanokorea.or.kr>)

The Chairman of Nano Korea Exhibition Committee announced that 250 companies and organizations participated as exhibitors at NANO KOREA 2010 with IEEE NANO 2010 exhibition. There were total of 425 booths at the exhibition, which was supported by its fine corporate members, which include the Samsung group.



The Chairman also said that this is the largest nanotechnology exhibition in Korea and is a platform for latest nanotechnologies. This year's theme was "Nano technology for the Green World", with the goal of finding solutions for environmental issues through nanotechnology. The conference reconfirmed Korea's position as the world's fourth largest nanotech developer.



We set up a booth in cooperation with our subsidiary, A&D Korea Limited, which is located in Seoul, Korea. We thank Mr. J.S.You, Mr. S.H. Han, Mr. T. Kogure and Ms. Yeo-Na, Kim at A&D Korea Limited for their cooperation in setting up A&D Company Limited's booth at #G18 in the Japan Papillion area. (Web site: <http://www.andk.co.kr/>)

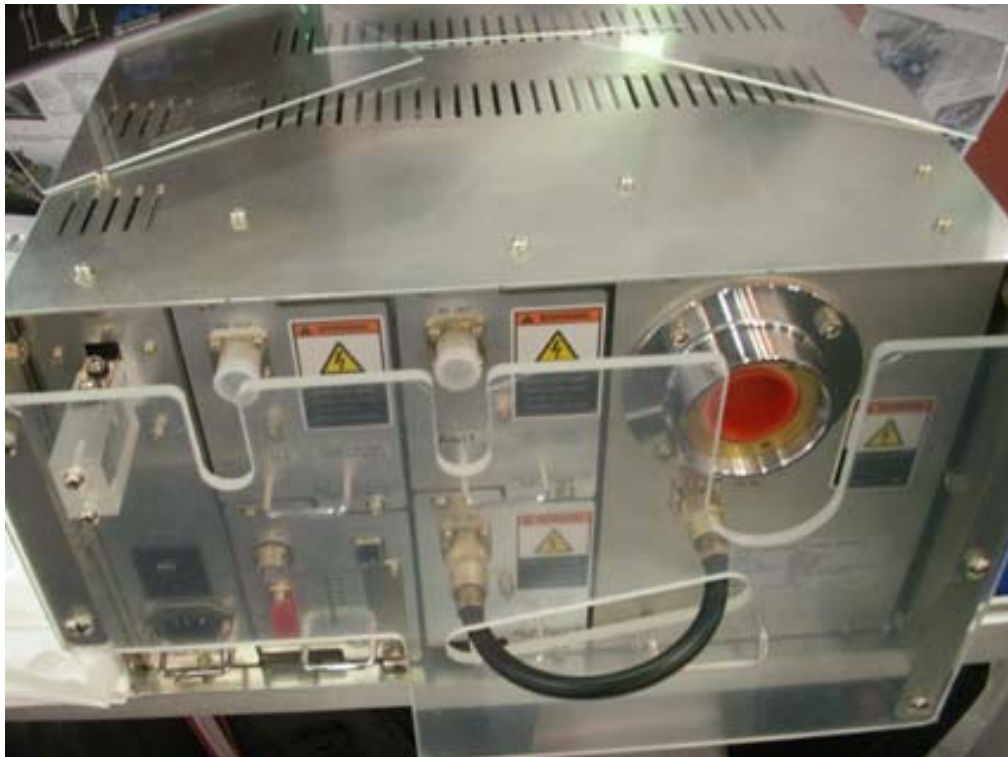
This was the 3rd opportunity for A&D Company Limited and A&D Korea Limited to participate in this exhibition and we displayed demonstrations of the following precision balances & moisture analyzers.

- The MS-70/MX-50/MF-50/ML-50 series of moisture analyzers
<http://www.aandd.jp/products/weighing/balance/moisture/mxmf.html>
- The FZ- I and FX-I series of precision balances
<http://www.aandd.jp/products/weighing/balance/toploader/fz-i.htm>
<http://www.aandd.jp/products/weighing/balance/toploader/fx-i.htm>



EB / FIB-related products were promoted by a 6-poster display and an introductory demonstration of the High Voltage Power Supply Model HV-30, which is designed for FIB and SEM field emitter instruments.

http://www.aandd.jp/products/test_measuring/eb/eb.html



We promoted A&D electron and ion beam products with the following six posters.



- **100kV Focused Ion Beam Implanter FIB100**
The FIB100 is designed for high voltage, high-resolution ion applications, such as ion implantation and micromachining.
- **Focused Ion Beam-TOF SIMS**
This model is designed for high-resolution material mapping with a spatial resolution of less than 40 nm. The FIB-TOF-SIMS (Focused Ion Beam Time-of-Flight Secondary Ion Mass Spectrometer) was developed by Toyama Co., Ltd., and incorporates A&D 's 30 kV Focused Ion Beam.
- **100kV Electron Beam Writer EBR401**
The EBR-401 model is equipped with a 100 kV electron beam and supports the development of discrete track and bit-patterned recording. It was developed by Pioneer FA Corporation and Pioneer Corporation.
- **FIB30 Focused Ion Beam**
The FIB30 is designed for high-resolution imaging. It is available for R&D, as well as for FIB system manufacturing.

- **FIB40 Focused Ion Beam**

The FIB40 is designed for high-resolution imaging and high-speed machining with a wide energy range.

- **High Voltage Power Supply, Motorized 10-Position Aperture Unit UHV Secondary Electron Detector**

This detector is designed for FIB and SEM field emitter instruments and components.

About 8,200 people attended the symposium and exhibition. To the attendees who visited our booth and requested for our catalogues, we thank you very much for your visit in Korea.